

**SN54LS189A, SN54LS219A, SN54LS289A, SN54LS319A  
 SN74LS189A, SN74LS219A, SN74LS289A, SN74LS319A  
 64-BIT RANDOM-ACCESS MEMORIES**

D2417, SEPTEMBER 1980 - REVISED FEBRUARY 1985

- Organized as 16 Words of Four Bits Each
- Choice of Buffered 3-State or Open-Collector outputs
- Choice of Noninverted or Inverted Outputs
- Typical Access Time . . . 50 ns

#### description

These monolithic TTL memories feature Schottky clamping for high performance and a fast chip-select access time to enhance decoding at the system level. A three-state output version and an open-collector-output version are offered for both of the logic choices. A three-state output offers the convenience of an open-collector output with the speed of a totem-pole output; it can be bus-connected to other similar outputs, yet it retains the fast rise time characteristic of the TTL totem-pole output. An open-collector output offers the capability of direct interface with a data line having a passive pull-up.

#### write cycle

Information to be stored in the memory is written into the selected address location when the chip-select ( $\bar{S}$ ) and the write-enable (R/W) inputs are low. While the write-enable input is low, the memory outputs are off (three-state = Hi-Z, open-collector = high). When a number of outputs are bus-connected, this off state neither loads nor drives the data bus; however, it permits the bus line to be driven by other active outputs or a passive pull-up.

#### read cycle

Information stored in the memory (see function table for input/output phase relationship) is available at the outputs when the write-enable input is high and the chip-select input is low. When the chip-select input is high, the outputs will be off.

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RAMs

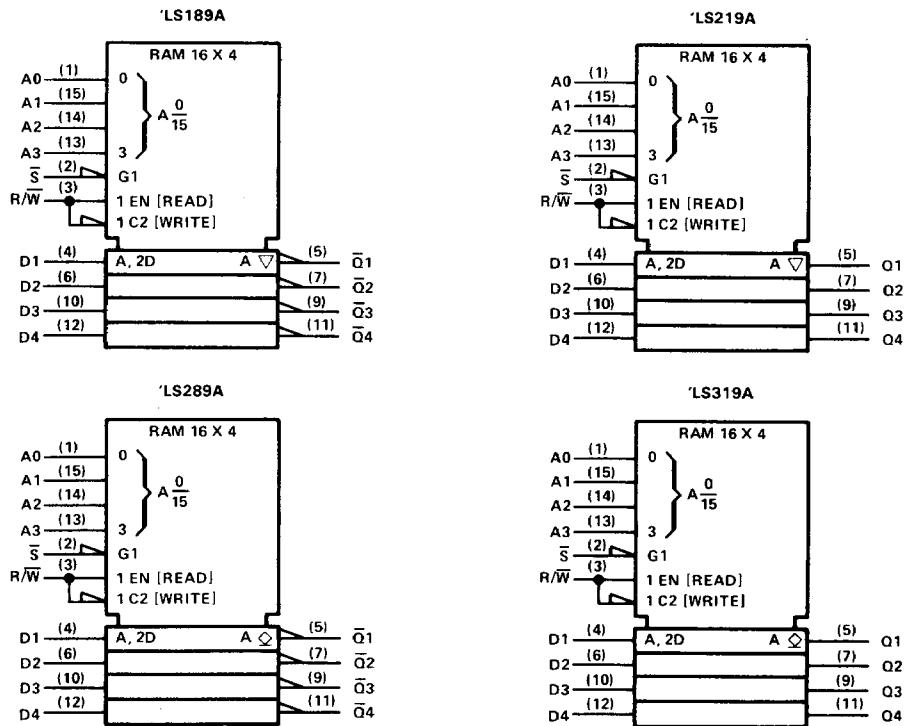
FUNCTION TABLE

FUNCTION	INPUTS		OUTPUTS			
	CHIP SELECT	WRITE ENABLE	'LS189A	'LS289A	'LS219A	'LS319A
Write	L	L	Z	Off	Z	Off
Read	L	H	Complement of Data Entered	Complement of Data Entered	Data Entered	Data Entered
Inhibit	H	X	Z	Off	Z	Off

H = high level, L = low level, X = irrelevant, Z = high impedance

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 64-BIT RANDOM-ACCESS MEMORIES**

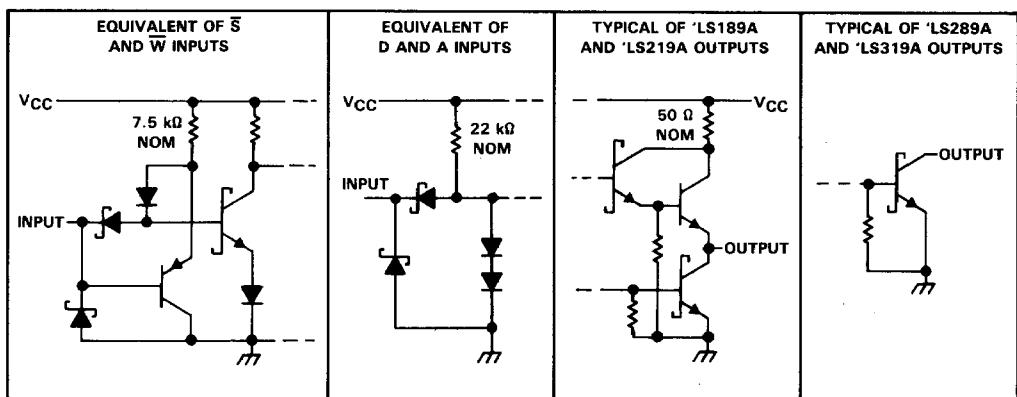
**logic symbols**



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**schematics of inputs and outputs**

**RAMs**



**SN54LS189A, SN54LS219A, SN54LS289A, SN54LS319A  
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 64-BIT RANDOM-ACCESS MEMORIES**

**absolute maximum ratings over operating free-air temperature range (unless otherwise noted)**

Supply voltage, V <sub>CC</sub> (see Note 1) . . . . .	7 V
Input voltage . . . . .	7 V
Off-state output voltage: 'LS189A, 'LS219A . . . . .	5.5 V
'LS289A, 'LS319A . . . . .	7 V
Operating free-air temperature range: SN54LS' Circuits . . . . .	-55°C to 125°C
SN74LS' Circuits . . . . .	0°C to 70°C
Storage temperature range . . . . .	-65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.

**recommended operating conditions**

		SN54LS189A, SN54LS219A			SN74LS189A, SN74LS219A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V <sub>CC</sub>		4.5	5	5.5	4.75	5	5.25	V
High-level output current, I <sub>OH</sub>				-1			-2.6	mA
Low-level output current, I <sub>OL</sub>				12			24	mA
Width of write pulse (write enable low), t <sub>w(wr)</sub>		100			70			
Setup time	Address before write pulse, t <sub>su(ad)</sub>	0I			0I			ns
	Data before end of write pulse, t <sub>su(da)</sub>	100I			60I			
	Chip-select before end of write pulse, t <sub>su(S)</sub>	100I			60I			
Hold time	Address after write pulse, t <sub>h(ad)</sub>	0I			0I			ns
	Data after write pulse, t <sub>h(da)</sub>	0I			0I			
	Chip select after write pulse, t <sub>h(S)</sub>	0I			0I			
Operating free-air temperature, T <sub>A</sub>		-55		125	0		70	°C

††The arrow indicates the transition of the write-enable input used for reference: ↓ for the low-to-high transition, ↑ for the high-to-low transition.

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RAMs

**SN54LS189A, SN54LS219A, SN74LS189A, SN74LS219A**  
**64-BIT RANDOM-ACCESS MEMORIES**  
**WITH 3-STATE OUTPUTS**

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS <sup>†</sup>	SN54LS189A			SN74LS189A			UNIT
		MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	
V <sub>IH</sub> High-level input voltage		2			2			V
V <sub>IL</sub> Low-level input voltage				0.7			0.8	V
V <sub>IK</sub> Input clamp voltage	V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA			-1.5			-1.5	V
V <sub>OH</sub> High-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = V <sub>ILmax</sub> , I <sub>OH</sub> = MAX	2.4	3.1		2.4	3.1		V
V <sub>OL</sub> Low-level output voltage	V <sub>CC</sub> = MIN, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = V <sub>ILmax</sub>	I <sub>OL</sub> = 12 mA I <sub>OL</sub> = 24 mA	0.25	0.4	0.25	0.4		V
I <sub>OZH</sub> Off-state output current, high-level voltage applied	V <sub>CC</sub> = MAX, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = V <sub>ILmax</sub> , V <sub>O</sub> = 2.7 V			20			20	μA
I <sub>OZL</sub> Off-state output current, low-level voltage applied	V <sub>CC</sub> = MAX, V <sub>IH</sub> = 2 V, V <sub>IL</sub> = V <sub>ILmax</sub> , V <sub>O</sub> = 0.4 V			-20			-20	μA
I <sub>I</sub> Input current at maximum input voltage	V <sub>CC</sub> = MAX, V <sub>I</sub> = 7 V			100			100	μA
I <sub>IH</sub> High-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 2.7 V			20			20	μA
I <sub>IL</sub> Low-level input current	V <sub>CC</sub> = MAX, V <sub>I</sub> = 0.4 V			-0.4			-0.4	mA
I <sub>OS</sub> Short-circuit output current <sup>§</sup>	V <sub>CC</sub> = MAX		-30	-130	-30	-130		mA
I <sub>CC</sub> Supply current	V <sub>CC</sub> = MAX, See Note 2		35	60	35	60		mA

<sup>†</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup>All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C.

<sup>§</sup>Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2: I<sub>CC</sub> is measured with the write-enable and chip-select inputs grounded, all other inputs at 4.5 V, and all outputs open.

**switching characteristics over recommended operating ranges of T<sub>A</sub> and V<sub>CC</sub> (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	SN54LS189A			SN74LS189A			UNIT
		MIN	TYP <sup>‡</sup>	MAX	MIN	TYP <sup>‡</sup>	MAX	
t <sub>a(ad)</sub> Access time from address		50	90		50	80		ns
t <sub>a(S)</sub> Access time from chip select (enable time)	C <sub>L</sub> = 45 pF, See Note 3	35	70		35	60		ns
tsr Sense recovery time		55	100		55	90		ns
tpxz Disable time from high or low level	from S from R/W	C <sub>L</sub> = 5 pF, See Note 3	30	60	30	50		ns
			40	70	40	60		

<sup>†</sup>All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°.

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

**SN54LS289A, SN54LS319A, SN74LS289A, SN74LS319A**  
**64-BIT RANDOM-ACCESS MEMORIES**  
**WITH OPEN-COLLECTOR OUTPUTS**

**recommended operating conditions**

		SN54LS289A, SN54LS319A			SN74LS289A, SN74LS319A			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	
		4.5	5	5.5	4.75	5	5.25	V
Supply voltage, $V_{CC}$					5.5		5.5	V
High-level output voltage, $V_{OH}$								
Low-level output current, $I_{OL}$					12		24	mA
Width of write pulse (write enable low), $t_{W(wr)}$		100			70			
Setup time	Address before write pulse, $t_{SU(ad)}$	01			01			ns
	Data before end of write pulse, $t_{SU(da)}$	1001			601			
	Chip-select before end of write pulse, $t_{SU(S)}$	1001			601			
Hold time	Address after write pulse, $t_{H(ad)}$	01			01			ns
	Data after write pulse, $t_{H(da)}$	01			01			
	Chip-select after write pulse, $t_{H(S)}$	01			01			
Operating free-air temperature, $T_A$		-55	125		0	70		°C

†The arrow indicates the transition of the write-enable input used for reference: ↑ for the low-to-high transition, ↓ for the high-to-low transition.

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER	TEST CONDITIONS†	SN54LS289A			SN74LS289A			UNIT	
		SN54LS319A			SN74LS319A				
		MIN	TYP‡	MAX	MIN	TYP‡	MAX		
$V_{IH}$ High-level input voltage		2			2			V	
$V_{IL}$ Low-level input voltage			0.7			0.8		V	
$V_{IK}$ Input clamp voltage	$V_{CC} = \text{MIN}, I_I = -18 \text{ mA}$			-1.5			-1.5	V	
$I_{OH}$ High-level output current	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, V_O = 2.4 \text{ V}$		20		20			μA	
	$V_{O} = 5.5 \text{ V}$		100		100				
$V_{OL}$ Low-level output voltage	$V_{CC} = \text{MIN}, V_{IH} = 2 \text{ V}, I_{OL} = 12 \text{ mA}$	0.25	0.4		0.25	0.4		V	
	$V_{IL} = V_{IL\text{max}}$			$I_{OL} = 24 \text{ mA}$		0.35	0.5		
$I_I$ Input current at maximum input voltage	$V_{CC} = \text{MAX}, V_I = 7 \text{ V}$		100		100			μA	
$I_{IH}$ High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7 \text{ V}$		20		20			μA	
$I_{IL}$ Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.4 \text{ V}$		-0.4		-0.4			mA	
$I_{CC}$ Supply current	$V_{CC} = \text{MAX}$ , See Note 2	35	60		35	60		mA	

†For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

‡All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

§Not more than one output should be shorted at a time and duration of the short circuit should not exceed one second.

NOTE 2:  $I_{CC}$  is measured with the write-enable and chip-select inputs grounded, all other inputs at 4.5 V, and all outputs open.

**switching characteristics over recommended operating ranges of  $T_A$  and  $V_{CC}$  (unless otherwise noted)**

PARAMETER	TEST CONDITIONS	SN54LS289A			SN74LS289A			UNIT	
		SN54LS319A			SN74LS319A				
		MIN	TYP‡	MAX	MIN	TYP‡	MAX		
$t_{a(ad)}$ Access time from address		50	90		50	80		ns	
$t_{a(S)}$ Access time from chip select (enable time)	$C_L = 45 \text{ pF}, R_L = 667\Omega$ , See Note 3	35	70		35	60		ns	
		55	100		55	90			
$t_{SR}$ Sense recovery time		30	60		30	50		ns	
		40	70		40	60			

‡All typical values are at  $V_{CC} = 5 \text{ V}, T_A = 25^\circ\text{C}$ .

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.

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RAMS